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Compl	ete if Known	
Application Number	10/081,309	
Filing Date	February 21, 2002	
First Name Inventor	Michael Brandt	
Group Art Unit	1644	
Examiner Name		
 Attorney Docket Number	20850	

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Number	r	ument Kind Code [:]	Name of Patentee or Appli Cited Document Pascal Sebastian Baile		Cited docume MM-DD-YY 02-15-2000	nt
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Examiner

Signature

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